

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M22-1313		PRIORITY SERIAL NO. 10443334	
LIST OF ART CITED BY APPLICANT <small>(Use several sheets if necessary)</small>				APPLICANT Cem Basceri et al.			
				PRIORITY FILING DATE May 21, 2003		PRIORITY GROUP 313	
U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
MA	AA 5,292,673	03-1994	Shinriki et al.				
MA	AB 5,486,488	01-1996	Kamiyama				
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						Yes	No
AK							
AL							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
MA	AM		Bin Yu, et al., "70nm MOSFET with Ultra-Shallow, Abrupt, and Super-Doped S/D Extension Implemented by Laser Thermal Process (LTP)", IEEE, 03/1999.				
MA	AN		Somit Talwar, et al., "Ultra-Shallow, Abrupt, and Highly-Activated Junctions by Low-Energy Ion Implantation and Laser Annealing", Verdant Technologies, San Jose, CA.				
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EXAMINER <i>Renee K. Ray</i>				DATE CONSIDERED <i>11-1-04</i>			
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY. DOCKET NO. M122-2515		SERIAL NO. 10/810,779	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)					APPLICANT Cem Basceri et al.			
					FILING DATE March 25, 2004		GROUP 2818	
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*Examiner Initial	Class	Document Number	Date	Name	Class	Subclass	Filing Date (if appropriate)	
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FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AM							
	AN							
	AO							
	AP							
	AQ							
OTHER REFERENCES (including Author, Title, Date, Portion Pages, Etc.)								
	AR							
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EXAMINER R. B. BERRY		DATE CONSIDERED 10-1-04						
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